



PHASICS
The phase control company



SID4-eSWIR

HIGH RESOLUTION EXTENDED SWIR WAVEFRONT SENSOR

The SID4-eSWIR wavefront sensor integrates PHASICS patented technology with a T2SL detector. Thanks to its high spatial resolution and great sensitivity, it offers accurate wavefront measurement over the extended SWIR range from 0.9 to 2.35 μm .

SID4-eSWIR is an innovative solution for testing SWIR sources and lenses used in optical communications, inspection instruments or night vision in military and surveillance devices. It provides both MTF and aberrations in one single shot.

APPLICATIONS: [Free-Space Optical Communication](#) | [Defense & Security](#) | [Aerospace](#)

SPECIFICATIONS

Wavelength range	0.9 - 2.35 μm
Aperture dimensions	9.60 x 7.68 mm ²
Phase spatial resolution	120 μm
Phase & Intensity sampling	80 x 64
Resolution (Phase)	< 6 nm RMS*
Accuracy	< 40 nm RMS*
Real-time processing frequency	> 10 Hz (full resolution)
Interface	USB 2.0
Dimensions	90 x 115 x 120 mm ³
Weight	~ 1.8 kg

* For coherent sources